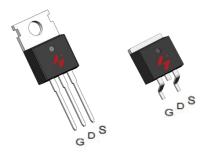


N-Channel Enhancement Mode MOSFET

Feature

- 100V/120A
 R_{DS(ON)}=6.8mΩ(typ.) @Ves = 10V
- 100% Avalanche Tested
- Reliable and Rugged
- Lead-Free and Green Devices Available (RoHS Compliant)

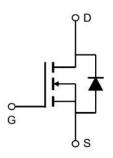
Pin Description



TO-220FB-3L TO-263-2L

Applications

- Power Switching application
- Uninterruptible Power Supply



N-Channel MOSFET

Ordering and Marking Information



Note: HUAYI lead-free products contain molding compounds/die attach materials and 100% matte tin plateTermi-Nation finish; which are fully compliant with RoHS. HUAYI lead-free products meet or exceed the lead-Free requirements of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. HUAYI defines "Green" to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Rat	tings (Tc=25°C Unless Otherwise Noted)			
VDSS	Drain-Source Voltage		100	V
Vgss	Gate-Source Voltage		±25	V
TJ	Maximum Junction Temperature		175	°C
Тѕтс	Storage Temperature Range		-55 to 175	°C
ls	Source Current-Continuous(Body Diode)	Tc=25°C	120	А
Mounted on	Large Heat Sink			
lрм	Pulsed Drain Current *	Tc=25°C	480**	А
1_	Continuous Drain Current	Tc=25°C	120	А
lσ	Continuous Drain Current Tc=100°C	Tc=100°C	84	А
Б	Maningura Dancar Dissination	Tc=25°C	237	W
Pb	Maximum Power Dissipation Tc=100°C		119	W
R _θ Jc	Thermal Resistance, Junction-to-Case		0.63	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient **		62.5	°C/W
Eas	Single Pulsed-Avalanche Energy ***	L=0.5mH	756***	mJ

Note: * Repetitive rating; pulse width limited by max. junction temperature.

** Surface mounted on FR-4 board.

*** Limited by TJmax, starting TJ=25°C, L = 0.5mH, VDS=80V, VGS =10V.

Electrical Characteristics (Tc = 25°C Unless Otherwise Noted)

Cumbal	Devenuetos	Test Conditions		HY3210		l lm!4	
Symbol	Parameter			Min	Тур.	Max	Unit
Static Cha	racteristics						
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _{DS} =2	250μA	100	-	-	V
less	V _{DS} =100V,V _{GS} =0V		-	-	1	μA	
IDSS	IDSS Drain-to-Source Leakage Current		T _J =125°C	-	-	10	μA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA		2.0	3.0	4.0	V
Igss	Gate-Source Leakage Current	V_{GS} = $\pm 25V$, V_{DS} = $0V$		-	-	±100	nA
RDS(ON)*	Drain-Source On-State Resistance	V _{GS} =10V,I _{DS} =60A		-	6.8	8.5	mΩ
Diode Cha	racteristics					•	
V _{SD} *	Diode Forward Voltage	IsD=60A,VGS=0V		-	0.8	1	V
trr	Reverse Recovery Time	- Isb=60A,dIsb/dt=100A/μs		-	46	-	ns
Qrr	Reverse Recovery Charge			-	98	-	nC



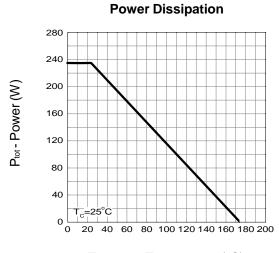
Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

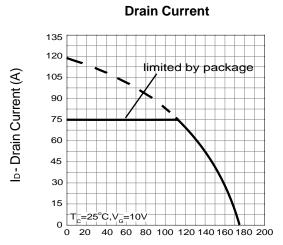
Or seeds at	Dome-monton.	Took Conditions		HY3210		
Symbol	Parameter	Test Conditions	Min	Тур.	Max	Unit
Dynamic	Characteristics					
Rg	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1 MHz	-	1.7	-	Ω
Ciss	Input Capacitance	V _{GS} =0V,	-	4922	-	
Coss	Output Capacitance	V _{DS} =25V,	-	902	-	pF
Crss	Reverse Transfer Capacitance	Frequency=1.0MHz	-	508	-	
td(ON)	Turn-on Delay Time		-	23	-	
Tr	Turn-on Rise Time	V_{DD} =50 V , R_{G} =6 Ω ,	-	35	-	
td(OFF)	Turn-off Delay Time	lps=60A,Vgs=10V	-	77	-	ns
Tf	Turn-off Fall Time		-	44	-	
Gate Cha	rge Characteristics					
Qg	Total Gate Charge	.,	-	120	-	
Qgs	Gate-Source Charge	V_{DS} =80V, V_{GS} =10V,	-	17	-	nC
Qgd	Gate-Drain Charge	וווי-סטר	-	28	-	

Note: *Pulse test, pulse width ≤ 300 us, duty cycle $\leq 2\%$



Typical Operating Characteristics

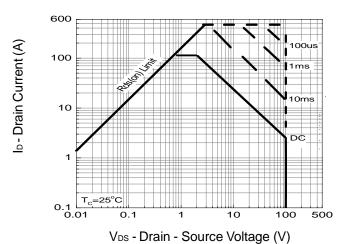




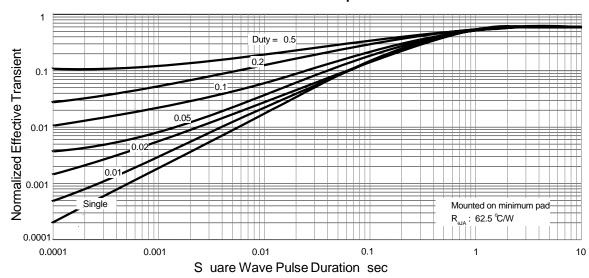
T_c- Case Temperature (°C)

Tc-Case Temperature (°C)

Safe Operation Area



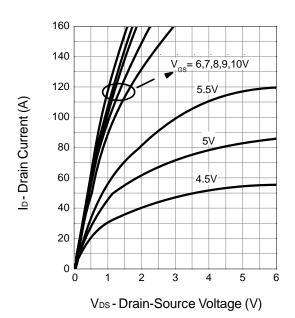
Thermal Transient Impedance



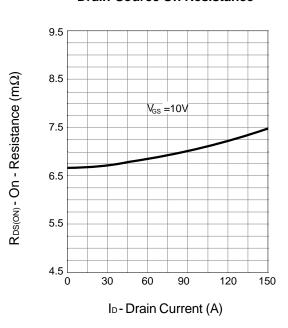


Typical Operating Characteristics (Cont.)

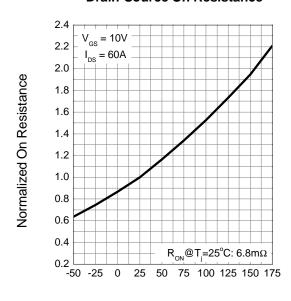
Output Characteristics



Drain-Source On Resistance

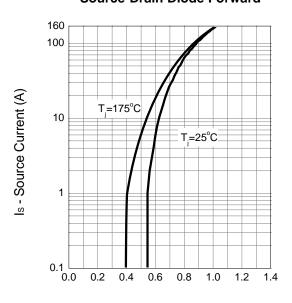


Drain-Source On Resistance



T_j- Junction Temperature (°C)

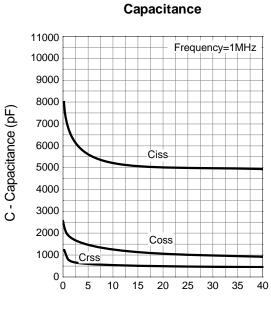
Source-Drain Diode Forward

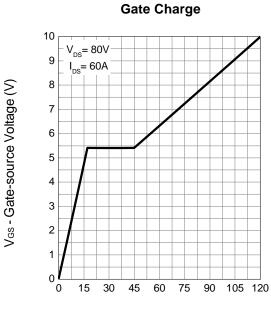


V_{SD} - Source-Drain Voltage (V)



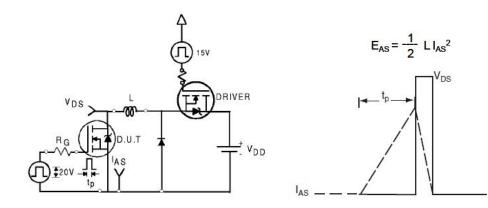
Typical Operating Characteristics (Cont.)



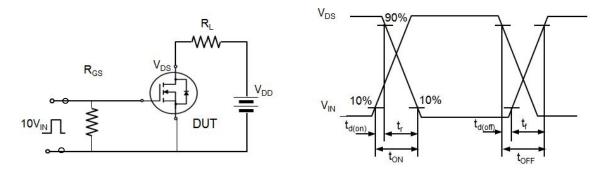




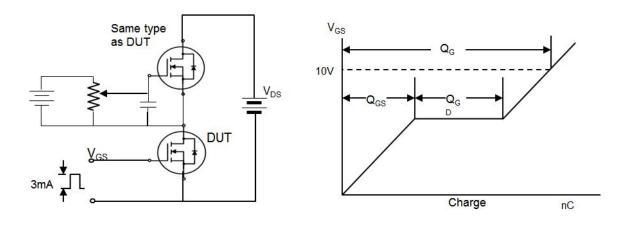
Avalanche Test Circuit



Switching Time Test Circuit



Gate Charge Test Circuit



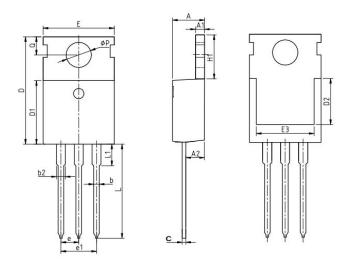


Device Per Unit

Package Type	Unit	Quantity
TO-220FB-3L	Tube	50
TO-263-2L	Tube	50

Package Information

TO-220FB-3L



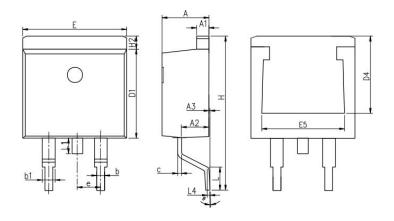
COMMON DIMENSIONS

SYMBOL	mm			
STIVIBUL	MIN	NOM	MAX	
А	4.37	4.57	4.77	
A1	1.25	1.30	1.45	
A2	2.20	2.40	2.60	
b	0.70	0.80	0.95	
b2	1.17	1.27	1.47	
С	0.40	0.50	0.65	
D	15.10	15.60	16.10	
D1	8.80	9.10	9.40	
D2	5.50	-	-	
E	9.70	10.00	10.30	
E3	7.00	-	-	
е		2.54 BSC		
e1		5.08 BSC		
H1	6.25 6.50 6.		6.85	
L	12.75	13.50	13.80	
L1	_	3.10	3.40	
ФР	3.40	3.60	3.80	
Q	2.60	2.80	3.00	



Package Information

TO-263-2L

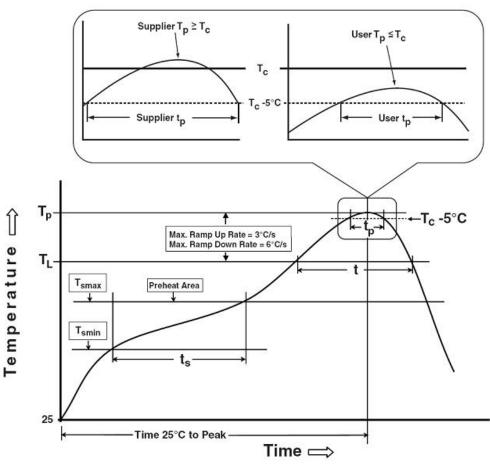


COMMON DIMENSIONS

SYMBOL		mm	
STIVIBUL	MIN	NOM	MAX
А	4.37	4.57	4.77
A1	1.22	1.27	1.42
A2	2.49	2.69	2.89
A3	0	0.13	0.25
b	0.7	0.81	0.96
b1	1.17	1.27	1.47
С	0.3	0.38	0.53
D1	8.5	8.7	8.9
D4	6.6	-	-
Е	9.86	10.16	10.36
E5	7.06	-	-
е		2.54 BSC	
Н	14.7	15.1	15.5
H2	1.07	1.27	1.47
L	2	2.3	2.6
L1	1.4	1.55	1.7
L4	0.25 BSC		
θ	0°	5°	9°



Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly		
Preheat & Soak Temperature min (T _{smin}) Temperature max (T _{smax}) Time (Tsmin to Tsmax) (t _s)	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds		
Average ramp-up rate (T _{smax} to T _P)	3 °C/second max.	3°C/second max.		
Liquidous temperature (T _L)	183 °C	217 °C		
Time at liquidous (t∟)	60-150 seconds	60-150 seconds		
Peak package body Temperature $(T_p)^*$	See Classification Temp in table 1	SeeClassification Tempin table 2		
Time (t _P)** within 5°C of the specified classification temperature (T _c)	20** seconds	30** seconds		
Average ramp-down rate (Tpto Tsmax)	6 °C/second max.	6 °C/second max.		
Time 25°C to peak temperature	6 minutes max.	8 minutes max.		
*Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.				

HY3210P/B



Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³
Thickness	<350	≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	168/500/1000 Hrs, Bias @ 150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
тст	JESD-22, A104	500 Cycles, -55°C~150°C

Customer Service

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